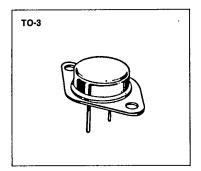
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## IRF340/341/342/343

### **N-CHANNEL POWER MOSFETS**

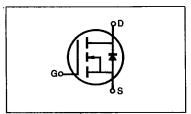
### **FEATURES**

- Low RDS(on)
- Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure
- Low input capacitance
- Extended safe operating area
- Improved high temperature reliability
- TO-3 package (Standard)



### **PRODUCT SUMMARY**

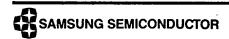
Part Number	V <sub>DS</sub>	R <sub>DS(on)</sub>	ID
IRF340	400V	0.55 Ω	10A
IRF341	35.0V	0.55 Ω	10A
IRF342	400V	0.80 Ω	8.0A
IRF343	350V	0.80Ω	8.0A



#### **MAXIMUM RATINGS**

Characteristic	Symbol	IRF340	IRF341	IRF342	IRF343	Unit
Drain-Source Voltage (1)	V <sub>DSS</sub>	400	350	400	350	Vdc
Drain-Gate Voltage (R <sub>GS</sub> =1.0MΩ)(1)	V <sub>DGR</sub>	400	350	400	350	Vdc
Gate-Source Voltage	V <sub>GS</sub>		±	20		Vdc
Continuous Drain Current T <sub>C</sub> =25°C	lo	10	10	8.0	8.0	Adc
Continuous Drain Current T <sub>C</sub> =100°C	lo	6.0	6.0	5.0	5.0	Adc
Drain Current—Pulsed (3)	Ірм	40	40	32	32	Adc
Gate Current—Pulsed	I <sub>GM</sub>		±.	1.5		Adc
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	P <sub>D</sub>			25 .0		Watts W/°C
Operating and Storage Junction Temperature Range	T <sub>J</sub> , Tstg		-55 to 150		°C	
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	TL		°C			

Notes: (1) T<sub>J</sub>=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2% (3) Repetitive rating: Pulse width limited by max. junction temperature



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**N-CHANNEL POWER MOSFETS** 

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub>=25°C unless otherwise specified)

Characteristic	Symbol	Туре	Mir	Тур	Max	Unit	Test Conditions	
Drain-Source Breakdown	BVDSS	IRF340 IRF342	1400	-	-	v	V <sub>GS</sub> =0V	
Voltage		IRF341 IRF343	1050	) _	_	٧	I <sub>D</sub> ≃250μA	
Gate Threshold Voltage	V <sub>GS(th)</sub>	ALL	2.0	_	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	
Gate-Source Leakage Forward	lass	ALL	-	-	100	nA	V <sub>GS</sub> =20V	
Gate-Source Leakage Reverse	lgss	ALL	_	<b> </b>	-100	nA	V <sub>GS</sub> =-20V	
Zero Gate Voltage Drain Current	loss	ALL	=	_	250	μА	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V	
			_	<u> </u>	1000	μΑ	V <sub>DS</sub> =Max. Rating×0.8, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C	
On-State Drain-Source	f <sub>D(on)</sub>	IRF340 IRF341	10	-	-	A		
Current (2)		IRF342 IRF343	8.0	_	-	Α	$V_{DS}>I_{D(on)}\times R_{DS(on)\ max.}, V_{GS}=10V$	
Static Drain-Source On-State		IRF340 IRF341	_	0.30	0.55	Ω		
Resistance (2)	ĺ	IRF342 IRF343	-	0.60	0.80	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =5.0A	
Forward Transconductance (2)	g <sub>fs</sub>	ALL	4.0	7.0	_	ช	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , i <sub>D</sub> =5.0A	
nput Capacitance	Ciss	ALL		1300	1600	pF	SS Story - Botton max. 10 C.O.	
Output Capacitance	Coss	ALL	_	250	450	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz	
Reverse Transfer Capacitance	Crss	ALL	_	50	150	pF	11. 150 2011. 1.00012	
urn-On Delay Time	t <sub>d(on)</sub>	ALL	-	_	35	ns	•	
Rise Time	tr	ALL	_	_	15	ns	V <sub>DD</sub> =0.5BV <sub>DSS</sub> , I <sub>D</sub> =5.0A, Z <sub>O</sub> =4.7Ω	
urn-Off Delay Time	t <sub>d(off)</sub>	ALL			90		(MOSFET switching times are essentially	
all Time	tf	ALL	_		35	ns	independent of operating temperature.)	
otal Gate Charge Gate-Source Plus Gate-Drain)	Qg	ALL	-	41	60	nC ,	V <sub>GS</sub> =10V, I <sub>D</sub> =12A, V <sub>DS</sub> =0.8 Max. Rating	
ate-Source Charge	Qgs	ALL	-1	6.0	_	nC (	Gate charge is essentially independent of	
ate-Drain ("Miller") Charge	Q <sub>gd</sub>	ALL	-1	35	_	nC C	operating temperature.)	

## THERMAL RESISTANCE

Junction-to-Case	RthJC	ALL	_		1.0	K/W
Case-to-Sink	RthCS	ALL	_	0.1	_	K/W Mounting surface flat, smooth, and greased
Junction-to-Ambient	RthJA	ALL	_	-		K/W Free Air Operation

Notes: (1) T<sub>J</sub>=25°C to 150°C (2) Pulse test: Pulse width≼300μs, Duty Cycle≤2% (3) Repetitive rating: Pulse width limited by max. junction temperature





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IRF340/341/342/343

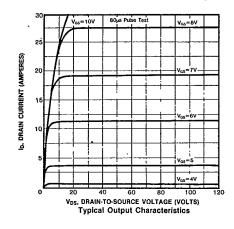
N-CHANNEL **POWER MOSFETS** 

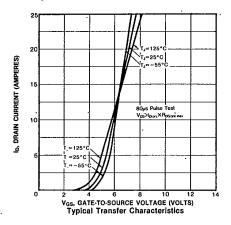
### SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

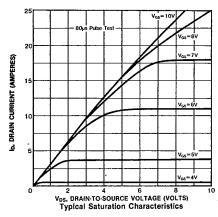
Characteristic	Symbol	Type	Min	Тур	Max	Units	Test Conditions
Continuous Source Current (Body Diode)		IRF340 IRF341	-	_	10	Α	
	IRF342 IRF343		_	8.0	А	Modified MOSFET symbol showing the integral	
Pulse Source Current		IRF340 IRF341	_	_	40	Α	reverse P-N junction rectifier
(Body Diode) (3)	Mei	IRF342 IRF343	·	_	32	Α	
Diode Forward Voltage (2)		IRF340 IRF341	<del></del>	_	2.0	٧	T <sub>C</sub> =25°C, I <sub>S</sub> =10A, V <sub>GS</sub> =0V
-	1 450	IRF342 IRF343	_	_	1.9	v	T <sub>C</sub> =25°C, I <sub>S</sub> =8.0A, V <sub>GS</sub> =0V
Reverse Recovery Time	t <sub>rr</sub>	ALL		800		ns	T <sub>J</sub> =150°C, I <sub>F</sub> =10A, dI <sub>F</sub> /dt=100A/μs

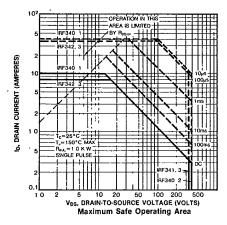
Notes: (1) T<sub>J</sub>=25°C to 150°C (2) Pulse test: Pulse width≤300µs, Duty Cycle≤2%

(3) Repetitive rating: Pulse width limited by max. junction temperature

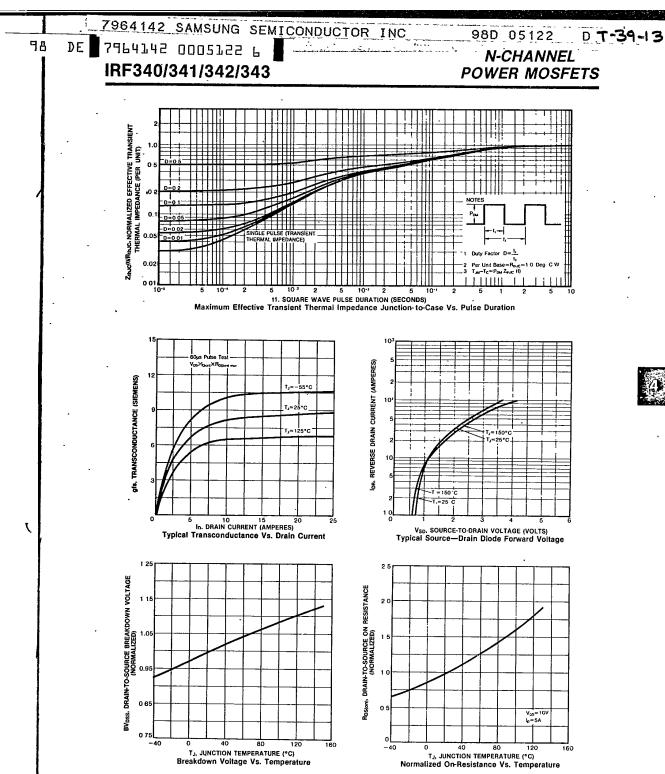








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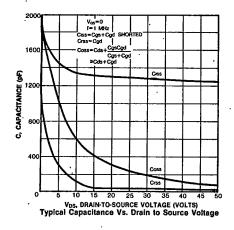


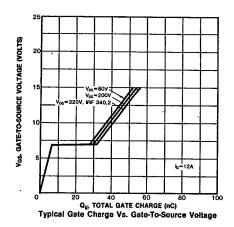


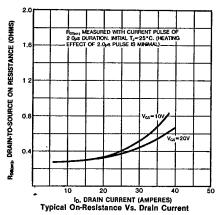
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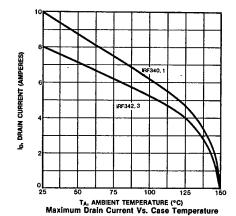
# IRF340/341/342/343

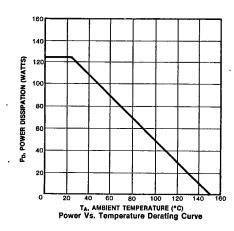
### **N-CHANNEL POWER MOSFETS**











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